

Fast fault emulation for synchronous sequential circuits

Raik, Jaan; Ellervee, Peeter; Tihhomirov, Valentin; Ubar, Raimund-Johannes Proceedings of East-West Design & Test

Workshop (EWDTW'04) : Yalta, Alushta, Crimea, Ukraine, September 23-26, 2004 2004 / p. 35-40

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GA-based test generation for sequential circuits

Brik, Marina; Raik, Jaan; Ubar, Raimund-Johannes; Ivask, Eero Proceedings of East-West Design & Test Workshop

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